

Dr. Ed Generazio NASA Langley Research Center

## Overview

Background

Sensor development & design issues

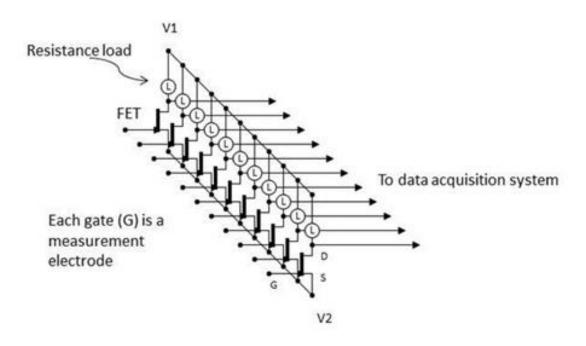
Electric field measurement systems

Application examples

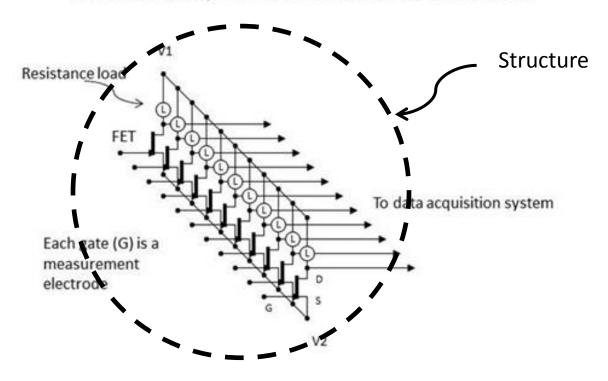
# Background

- NDE historically has focused technology development in propagating wave phenomena:
  - X-ray, ultrasonic, microwave, thermal, terahertz, and eddy current
  - Little attention to the field of electrostatics and emanating electric fields.
- Interest in evaluating the integrity of wire insulation in aircraft and aerospace systems
- This work is based on the original electric field sensor (e-Sensor) work disclosed by Generazio (2002).

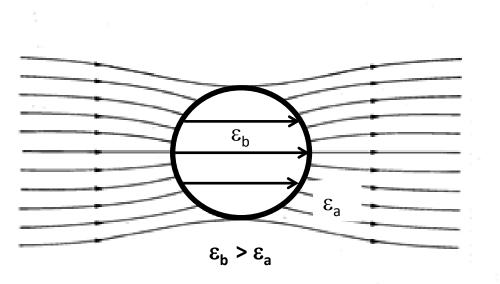
#### e-Sensor Array Based on Field Effect Transistors

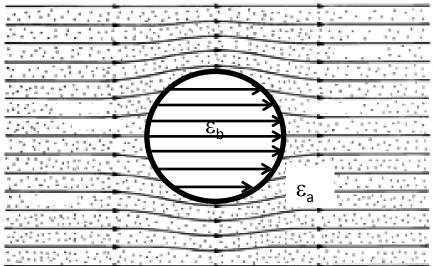


#### e-Sensor Array Based on Field Effect Transistors



Floating gate design



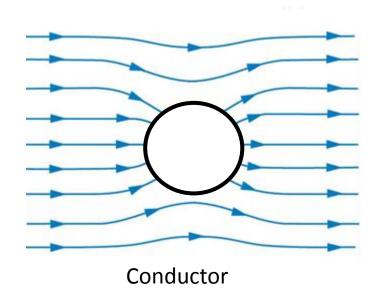


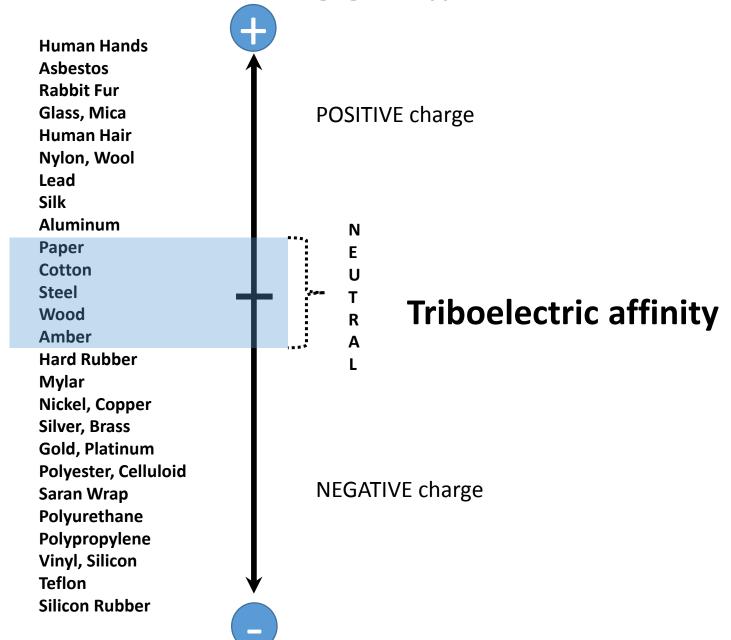
 $\varepsilon_{\rm b} \leq \varepsilon_{\rm a}$ 

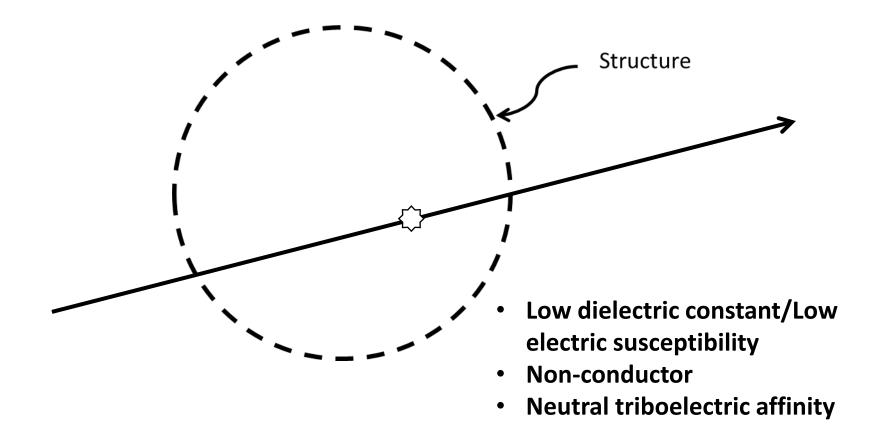
Dielectric constant, relative permittivity,  $\boldsymbol{\epsilon}$ 

Electric susceptibility,  $\chi = 1 - \epsilon$ 

 $\varepsilon$  = 1 vacuum







## Catch 22

 Want to select the best materials for constructing an electric field measurement system, however, the actual electrical properties vary or are unknown in configuration to be used.

- Insulation on wiring
- Wire diameters
- Circuit elements
- Support materials

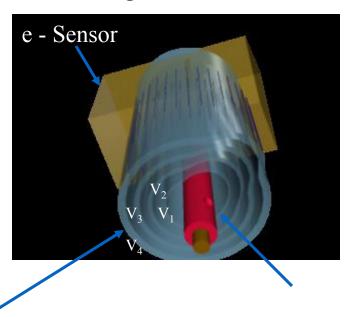
Don't know actual electrical properties until tested

### An Example, "e - Sensor" Antenna Configuration for Wiring Inspection

#### New Insulation

# e - Sensor V<sub>2</sub> V<sub>3</sub> V<sub>4</sub>

#### **Damaged Insulation**



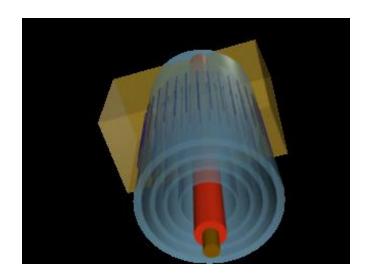
Equipotential surfaces

Damaged insulation

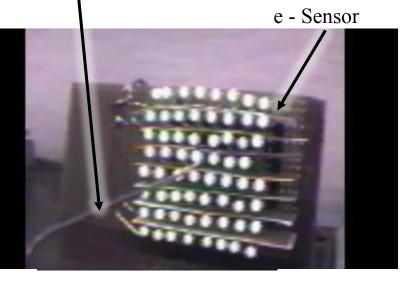
Electrical equipotential surfaces  $(V_1, V_2, V_3, V_4)$  are distorted due to damaged or aged insulation. Some antenna elements are no longer parallel to the electrical equipotential surfaces and now are exposed to an increase in potential.

The electric field, **E**, at any point is given by  $-\overrightarrow{\nabla}V = \overrightarrow{E}$ , where V is the electrical potential

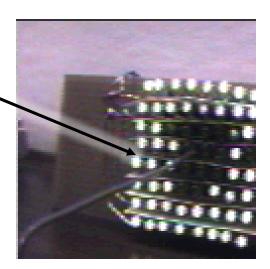
## "e - Sensor" Data from Prototype



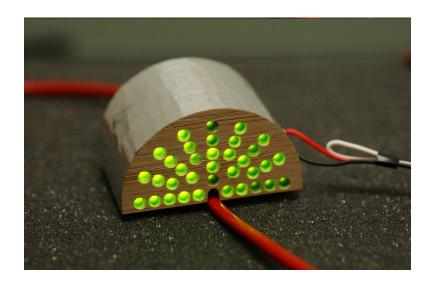
Wire passing through e - Sensor prototype

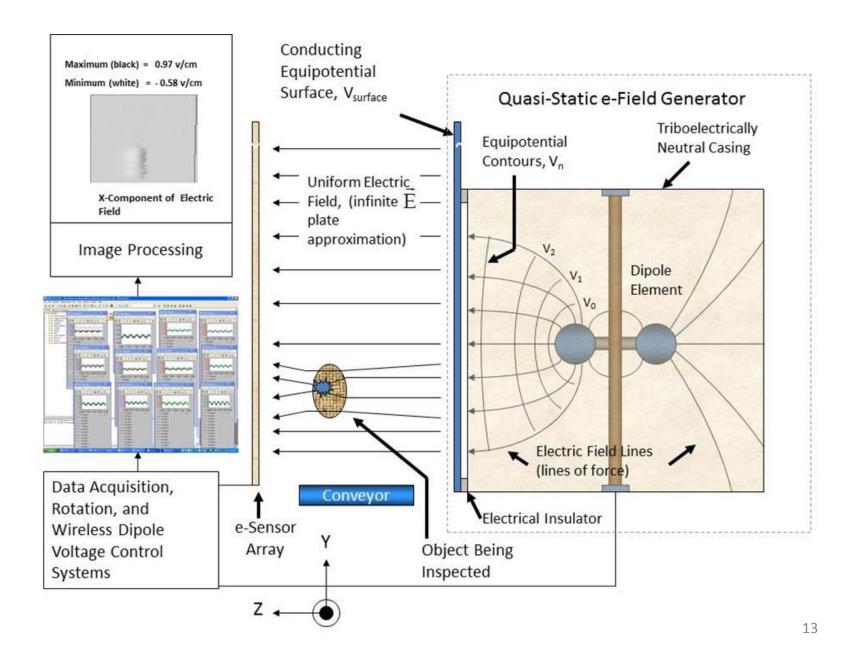


e - Sensor LEDs are dimmed proportionately by the presence of the spatially varying electric potential existing around statically charged insulated wire.

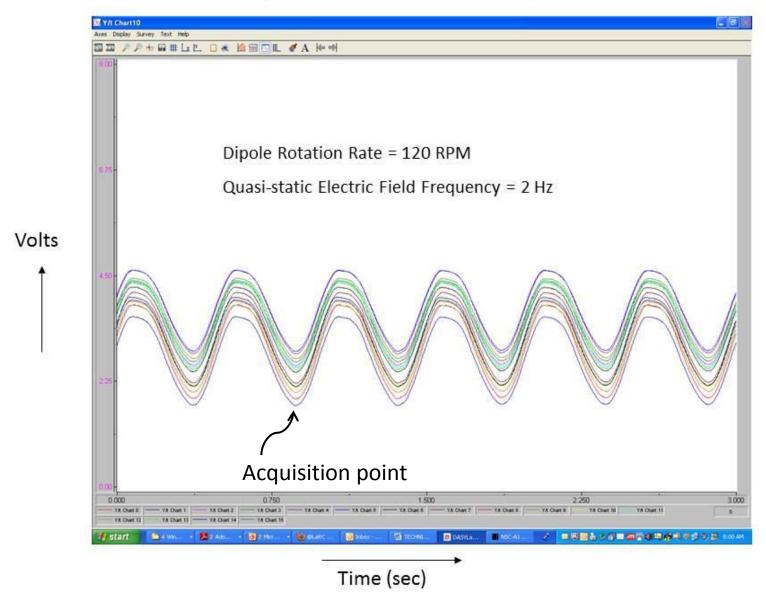


## 2<sup>nd</sup> Prototype





#### Voltage Response from 16 e-Sensors





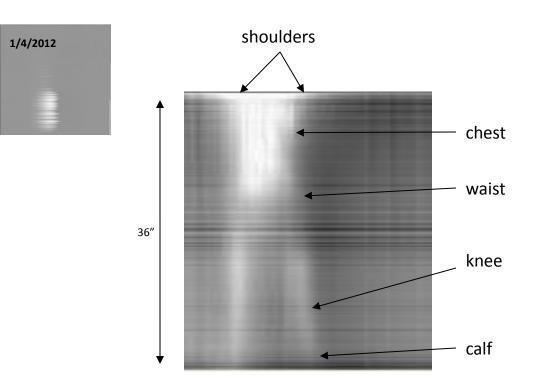






#### **Electric Potential Image of Human**

Using Electric Field Imaging (2016) US 9279719 B2 & Quasi-Static Electric Field Generator (2016) US20160049885A1



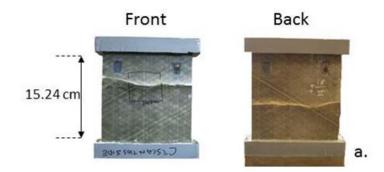


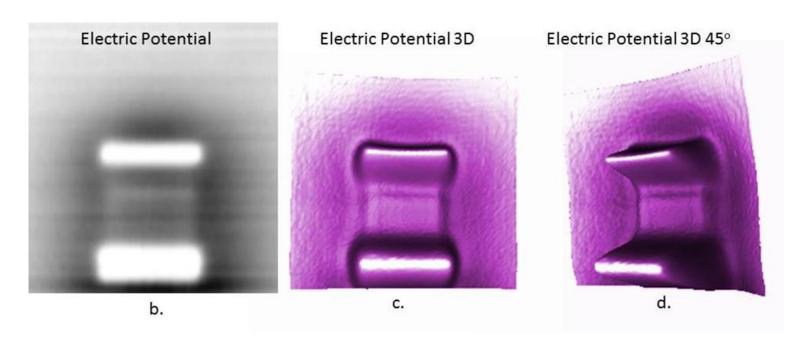
Ed Generazio's

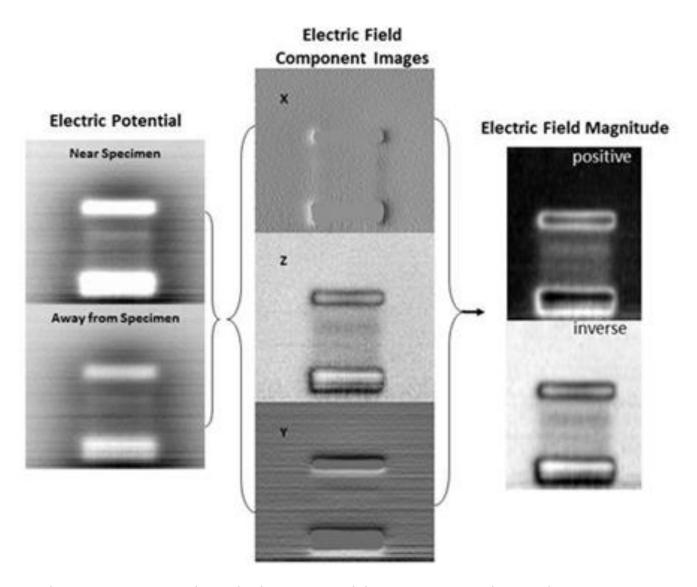
1<sup>st</sup> electric field image of a human, 10/23/2012

Electrical potential image of a human in a uniform electric field

- First images identify rich areas of improvement.
- Imaging volumetric dielectric properties of structures







Generazio, E. R., *Electric Potential and Electric Field Imaging with Applications*, Materials Evaluation, November 2015, pgs. 1479 - 1489

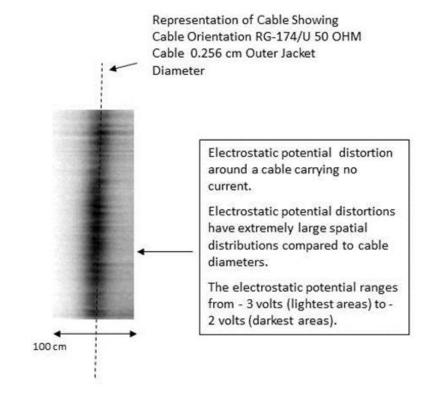
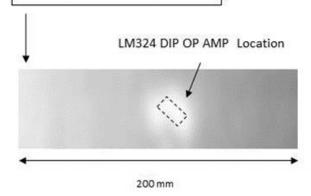
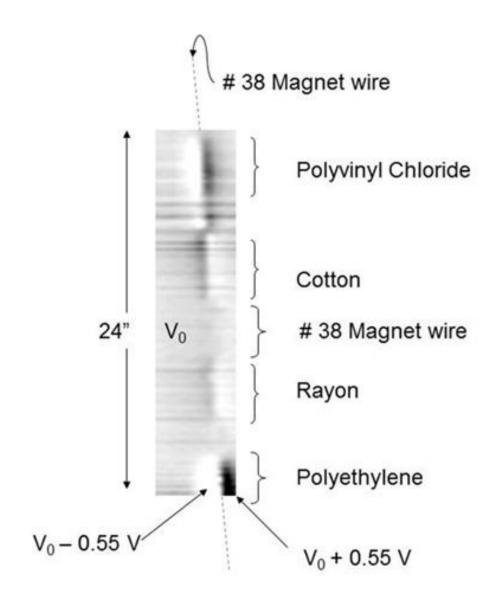


Image of actual electrostatic potential distortion around LM324 Operational Amplifier (LM324 DIP), 10 mm x 20 mm top surface is normal to reference electric field.

Electrostatic potential distortions have extremely large spatial distributions compared to amplifier dimensions.

The electrostatic potential ranges from - 3 volts (darkest areas) to - 4 volts (lightest areas).

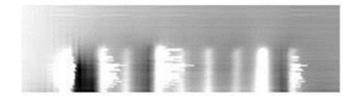




As received rods







Silk cloth passed over surface

Dielectric Constant ε		Triboelectric Affinity
2.7	Acrylic	-10
1.2 - 2.1	Wood	+7
3	Nylon	+30
5 – 5	Garolite	+30
4 - 9	Mica ceramic	
3.8	Borosilicate Glass	+25
	Copper	~0
2.8 - 4.1	Polyester	-40

Samples are in order left to right

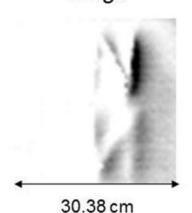
#### EFI: New Electrostatic Eyes



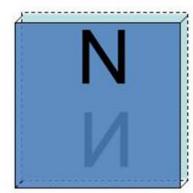


EFI Electrostatic Potential Image of latent charge distribution generated by triboelectrically drawing the letters "NASA" on PTFE. The EFI image is ovelaid onto the area scanned.

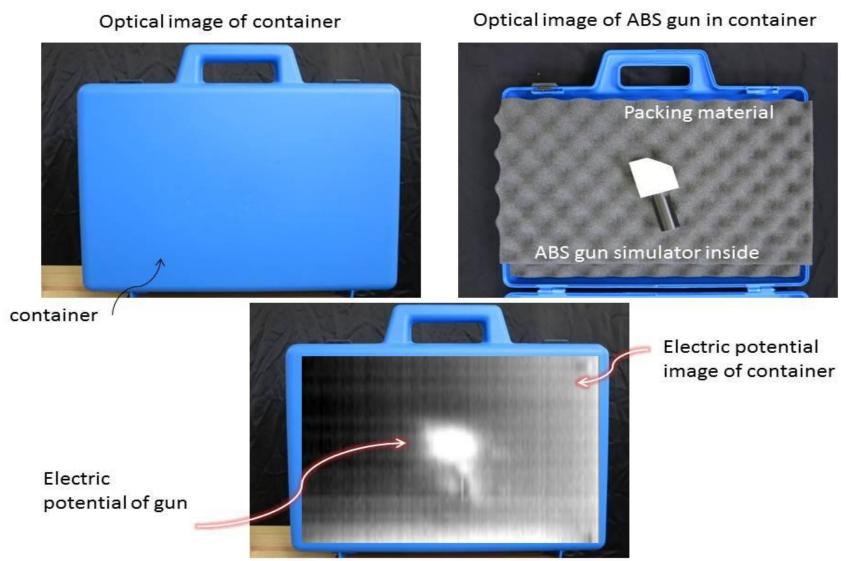
#### Electric Potential Image



PTFE, Teflon Panel 6.35 mm x 30.38 cm x 30.38 cm

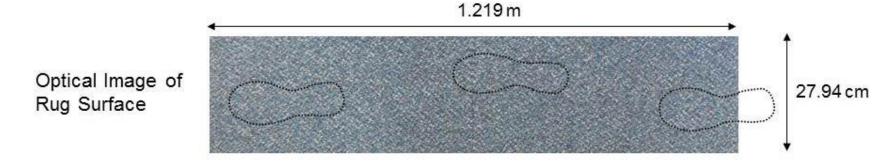


The letter "N" triboelectrically hand drawn on the front (upper) and back (lower) of a PTFE panel.



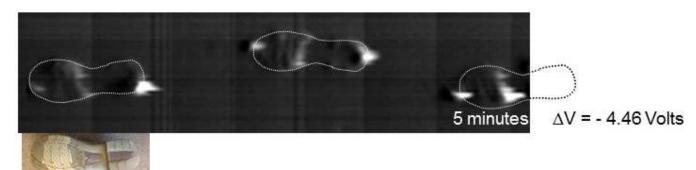
#### Foot Prints on Static Protection Office Rug

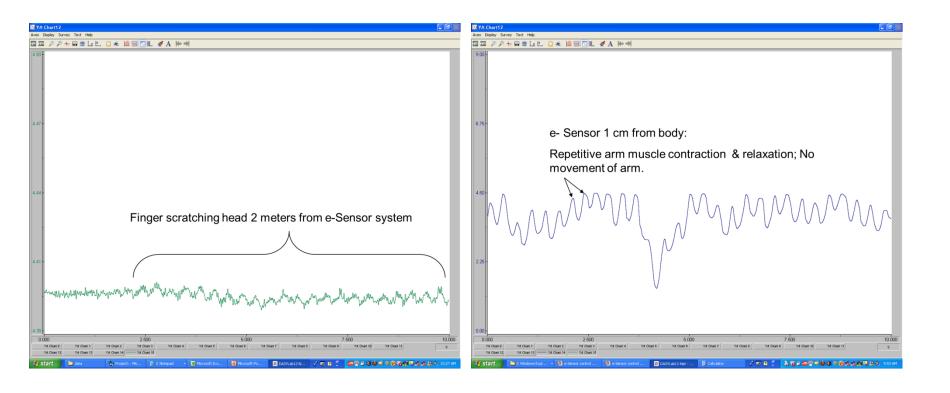
Footfalls are outlined in dashed curves



EFI Image (electrical potential)

Optical Image of Bottom of Right Shoe

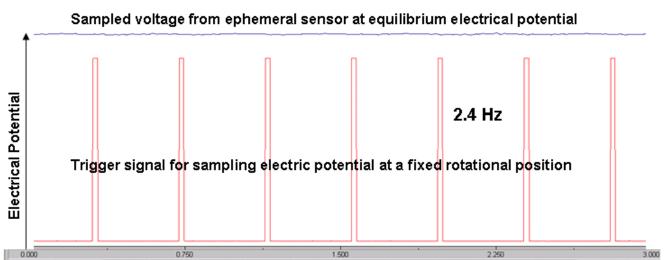


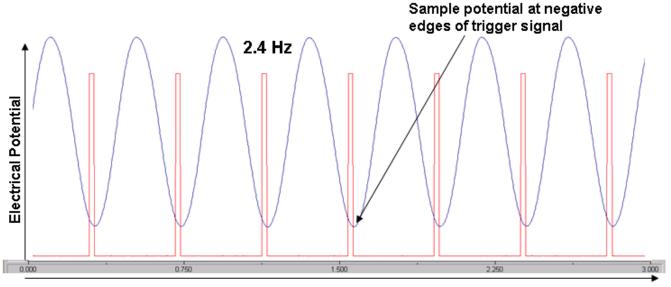


Very conservative sensitivity at 1.55mV/cm

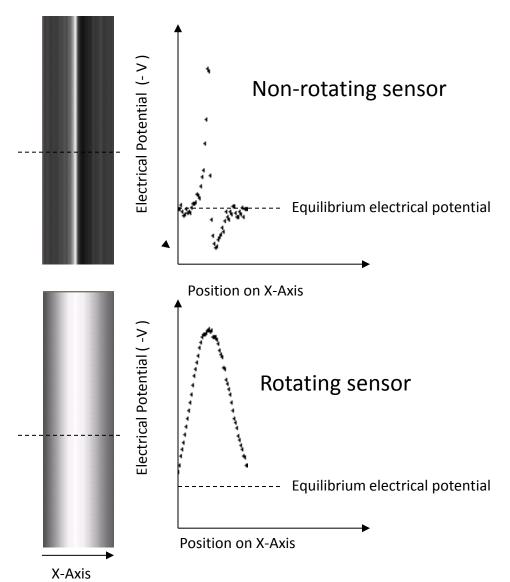
Several orders of magnitude by FET selection, components, filtering, structural design, etc.

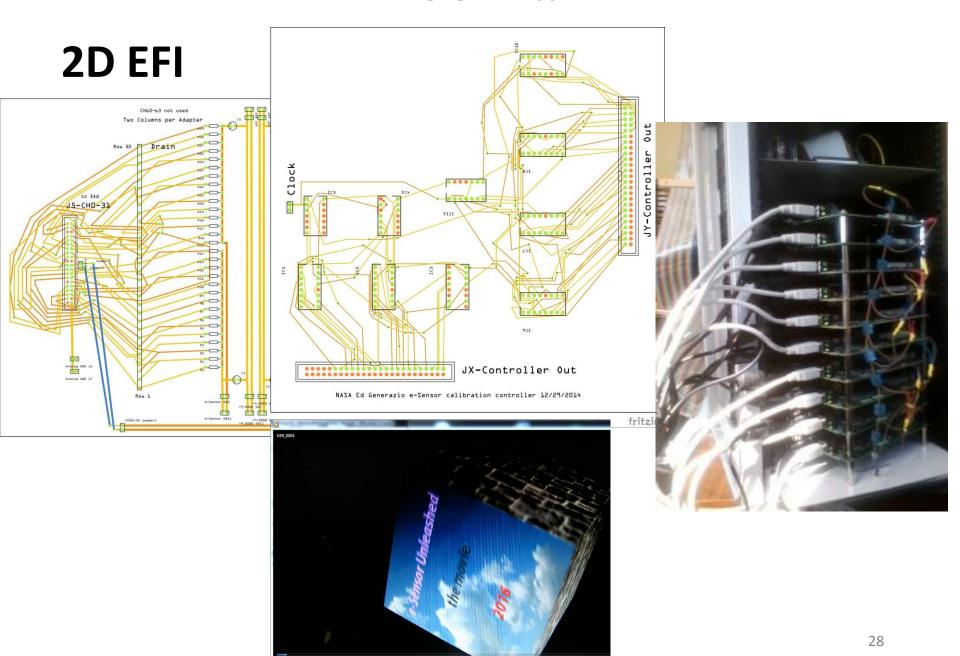
## True Electric Potential Measurements are Made When Sensor is in Quasi-static Motion





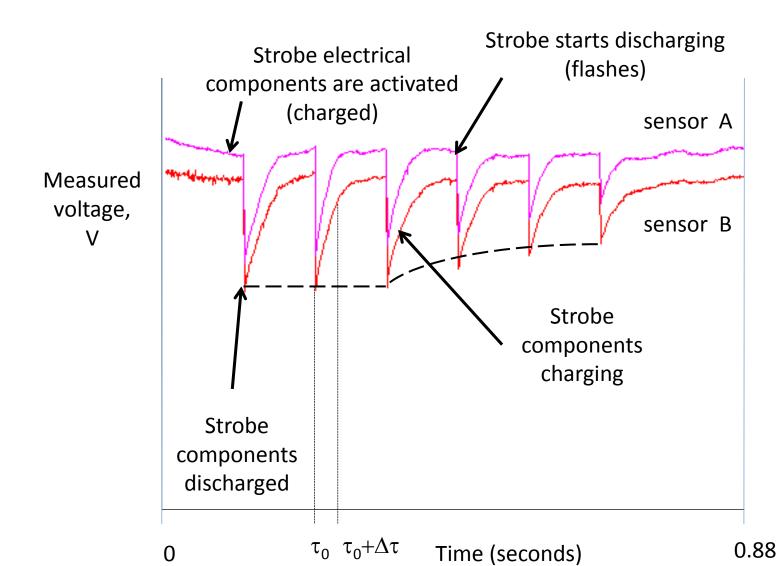
#### Typical Measured Ephemeral Sensor Response in the Presence of a Charged Axially Symmetric Object

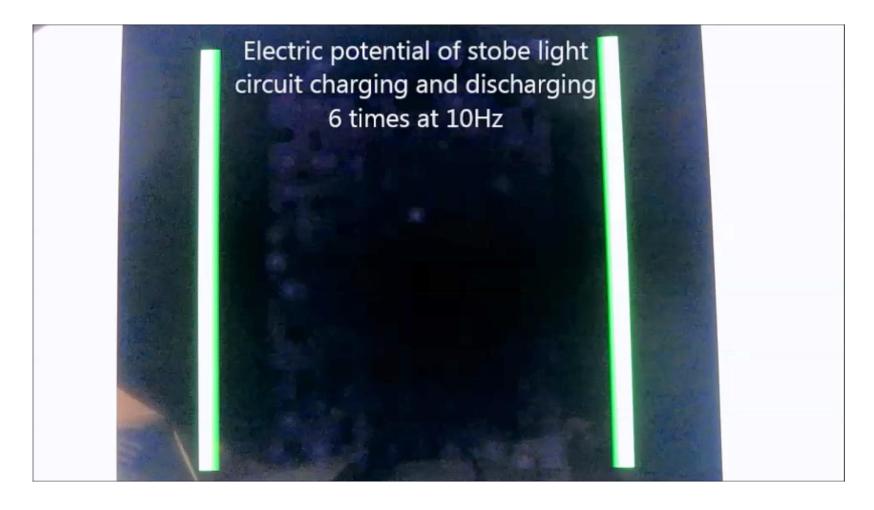






# Individual element sensor responses due to changes in strobe circuit electrical potentials





Strobe lamp flash

$$\Delta \tau = 0.060 \text{ sec}$$





# **Anticipated Benefits**

#### NASA Programs and Commercial space industry

- Electrostatic discharge (ESD) control requirements
- Damaged materials characterization requirements
- Component operations and integrity
- Tether quality control
- Lightening Prediction
- Vehicle and component charging requirements
- Design and construction of unique electronic sensors
- Systems and human health monitoring in space.
- Atmospheric Imaging

#### • The Nation

- Medical non-contact EKG and EMG (electromyography)
- Intrusion detection
- US perimeter security
- Transportation security- personnel and baggage inspection
- Personnel identification and access
- Electronic signature requirements

## Q & A

- Electric Field Imaging (2016) US 9279719 B2
- Quasi-Static Electric Field Generator (2016) US20160049885A1
- Ephemeral Electric Potential and Electric Field Sensor (2015) US20150137825
- Solid State Ephemeral Electric Potential and Electric Filed Sensor, Serial Number: 15/177,798 (2016)

For EFI technology listing and licensing opportunities:

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757-342-5569

https://technology.nasa.gov/patent/LAR-TOPS-116

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